

# APT20M18B2VR A20M18LVR

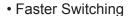
200V 100A 0.018Ω

# POWER MOS V® MOSFET

Power MOS  $V^{\otimes}$  is a new generation of high voltage N-Channel enhancement mode power MOSFETs. This new technology minimizes the JFET effect, increases packing density and reduces the on-resistance. Power MOS  $V^{\otimes}$  also achieves faster switching speeds through optimized gate layout.



Avalanche Energy Rated



Lower Leakage



#### MAXIMUM RATINGS

All Ratings:  $T_C = 25^{\circ}C$  unless otherwise specified.

Symbol	Parameter	APT20M18B2VR LVR	UNIT		
V <sub>DSS</sub>	Drain-Source Voltage	200	Volts		
I <sub>D</sub>	Continuous Drain Current <sup>©</sup> @ T <sub>C</sub> = 25°C	100	Amps		
I <sub>DM</sub>	Pulsed Drain Current ①	400	Ailibs		
V <sub>GS</sub>	Gate-Source Voltage Continuous	±30	Volts		
V <sub>GSM</sub>	Gate-Source Voltage Transient	±40	VOILO		
$P_{D}$	Total Power Dissipation @ T <sub>C</sub> = 25°C	625	Watts		
	Linear Derating Factor	5.00	W/°C		
$T_J, T_STG$	Operating and Storage Junction Temperature Range	-55 to 150	°C		
T <sub>L</sub>	Lead Temperature: 0.063" from Case for 10 Sec.	300			
I <sub>AR</sub>	Avalanche Current (1) (Repetitive and Non-Repetitive)	100	Amps		
E <sub>AR</sub>	Repetitive Avalanche Energy ①	50	mJ		
E <sub>AS</sub>	Single Pulse Avalanche Energy <sup>(4)</sup>	3000	10		

### STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage ( $V_{GS} = 0V$ , $I_D = 250\mu A$ )	200			Volts
R <sub>DS(on)</sub>	Drain-Source On-State Resistance $^{\textcircled{2}}$ (V <sub>GS</sub> = 15V, I <sub>D</sub> = 50A)			0.018	Ohms
I <sub>DSS</sub>	Zero Gate Voltage Drain Current ( $V_{DS} = 200V, V_{GS} = 0V$ )			25	μΑ
	Zero Gate Voltage Drain Current ( $V_{DS}$ = 160V, $V_{GS}$ = 0V, $T_{C}$ = 125°C)			250	
I <sub>GSS</sub>	Gate-Source Leakage Current $(V_{GS} = \pm 30V, V_{DS} = 0V)$			±100	nA
$V_{GS(th)}$	Gate Threshold Voltage $(V_{DS} = V_{GS}, I_{D} = 2.5 \text{mA})$	2		4	Volts

CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> = 0V		9880		
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 25V		2320		рF
C <sub>rss</sub>	Reverse Transfer Capacitance	f = 1 MHz		700		
Q <sub>g</sub>	Total Gate Charge <sup>③</sup>	V <sub>GS</sub> = 10V		330		
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DD</sub> = 150V		55		nC
$Q_{gd}$	Gate-Drain ("Miller") Charge	I <sub>D</sub> = 100A @ 25°C		145		
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>GS</sub> = 15V		18		
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 150V		27		ns
t <sub>d(off)</sub>	Turn-off Delay Time	I <sub>D</sub> = 100A @ 25°C		55		110
t <sub>f</sub>	Fall Time	$R_{G} = 0.6\Omega$		6		

#### SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT	
Is	Continuous Source Current (Body Diode)			100	Amps	
I <sub>SM</sub>	Pulsed Source Current (1) (Body Diode)			400	7 111100	
V <sub>SD</sub>	Diode Forward Voltage $^{(2)}$ (V <sub>GS</sub> = 0V, I <sub>S</sub> = -49A)			1.3	Volts	
t <sub>rr</sub>	Reverse Recovery Time $(I_S = -49A, dI_S/dt = 100A/\mu s)$		360		ns	
Q <sub>rr</sub>	Reverse Recovery Charge (I <sub>S</sub> = -49A, dI <sub>S</sub> /dt = 100A/µs)		6.7		μC	
dv/ dt	Peak Diode Recovery <sup>dv</sup> / <sub>dt</sub> <sup>(5)</sup>			5	V/ns	

### THERMAL CHARACTERISTICS

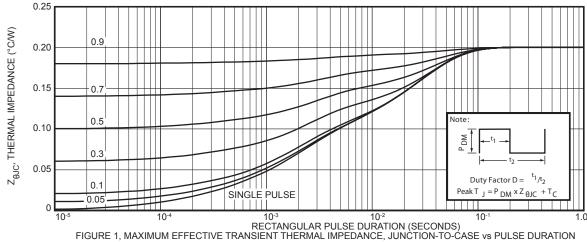
Symbol	Characteristic	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction to Case			0.20	°C/W
$R_{\theta JA}$	Junction to Ambient			40	0, 11

① Repetitive Rating: Pulse width limited by maximum junction temperature

- $\odot$  Pulse Test: Pulse width < 380  $\mu$ s, Duty Cycle < 2%
- 3 See MIL-STD-750 Method 3471

- (a) Starting T<sub>j</sub> = +25°C, L = 600µH, R<sub>G</sub> = 25 $\Omega$ , Peak I<sub>L</sub> = 100A (b) dv/<sub>dt</sub> numbers reflect the limitations of the test circuit rather than the device itself. I<sub>S</sub> ≤ -I<sub>D</sub>100A di/<sub>dt</sub> ≤ 200A/µs  $V_R$  ≤ 200V  $T_J$  ≤ 150°C (f) The maximum current is limited by lead temperature.

Microsemi reserves the right to change, without notice, the specifications and information contained herein.



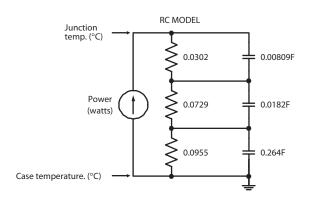
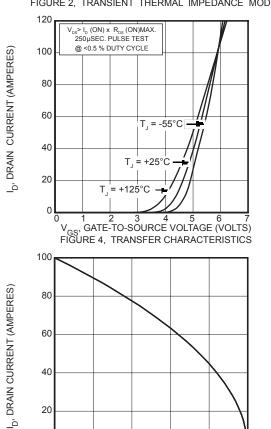
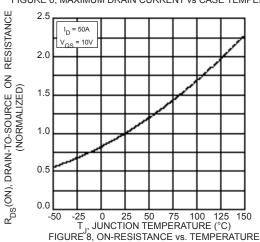
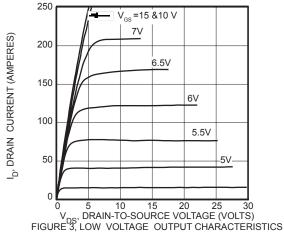


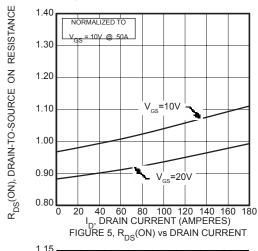
FIGURE 2, TRANSIENT THERMAL IMPEDANCE MODEL

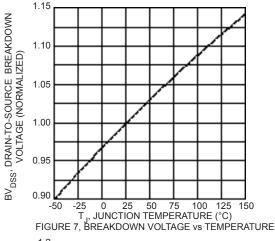


25 50 75 100 125 150 T<sub>C</sub>, CASE TEMPERATURE (°C) FIGURE 6, MAXIMUM DRAIN CURRENT vs CASE TEMPERATURE









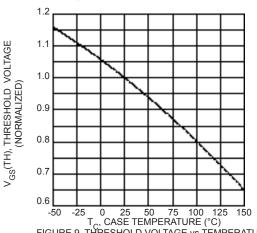
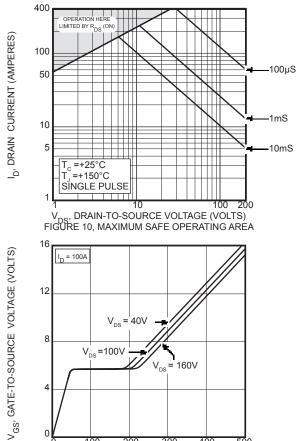


FIGURE 9, THRESHOLD VOLTAGE vs TEMPERATURE

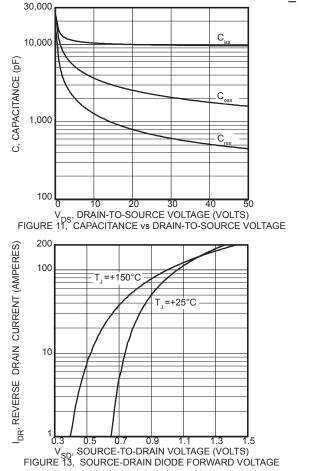


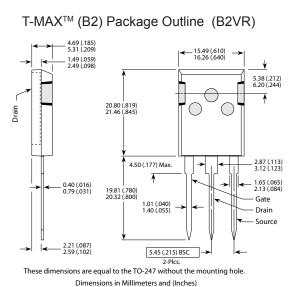
300

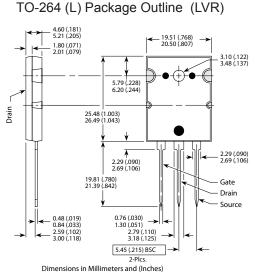
400

200

 $\rm Q_{\rm g}$  , TOTAL GATE CHARGE (nC) FIGURE 12, GATE CHARGE vs GATE-TO-SOURCE VOLTAGE TOTAL GATE CHARGE (nC)







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